深圳市炬烜科技有限公司 CHIP SUN TECHNOLOGY CO., LTD

APPROVAL Sheet



CUSTOMER:	Quartz 1
DESCRIPTION:	SMD3.2*1.5 32.768KHz Quartz Crystal Resonator
MANUFACTURER PART NO.:	FTX32.768K4.0SM3-20D
CUSTOMER PART NO:	
USED IN MODEL :	
REVISION	A1

	承	认	A	PPROVAL
工程部	r F	品质部		采购部
TECHNOLOGY DEPT.	QUA	LITY DEPT.		PURCHASING DEPT.

Date: <u>June 15, 2023</u>



深圳市炬烜科技有限公司

CHIP SUN TECHNOLOGY CO., LTD

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<u>Rev</u>	<u>Revise page</u>	<u>Revise contents</u>	Date	<u>Ref.No.</u>	Reviser
A1	ALL	Initial released		N/A	DavidJiang

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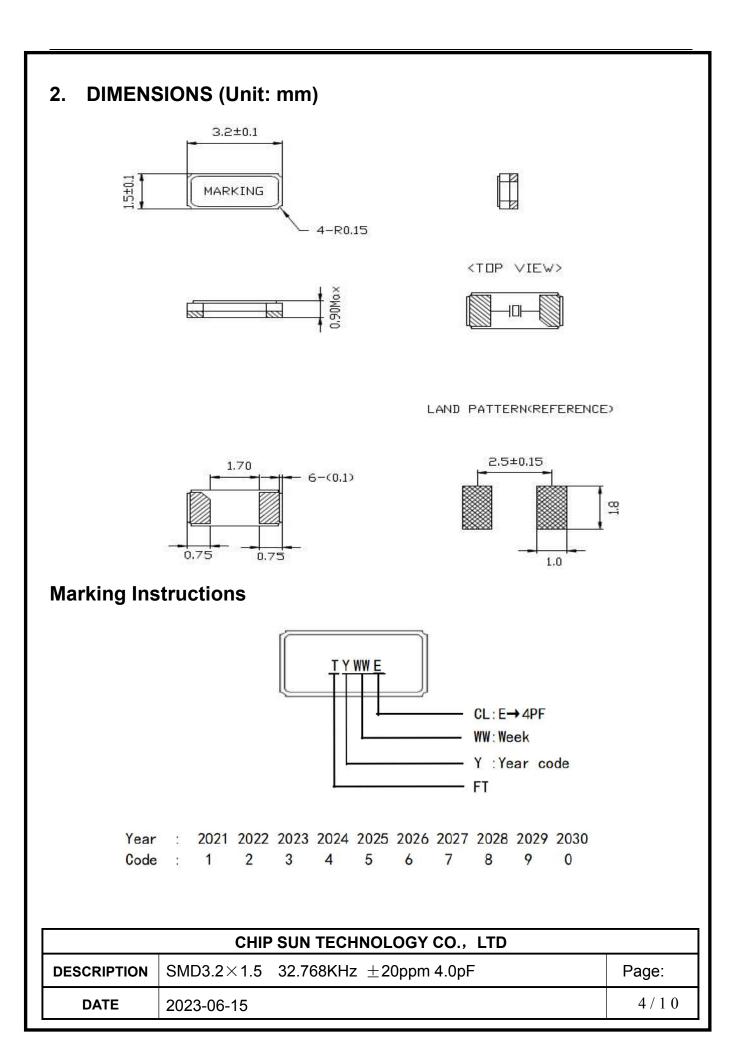
1. QUARTZ CRYSTAL UNIT SPECIFICATION

Parameter	Specification			
1.1 Frequency:	32.768KHz			
1.2 Holder type :	SMD3.2×1.5×0.8 mm			
1.3 Frequency tolerance:	±20ppm at 25℃			
1.4 Equivalent resistance:	70Kohms Max			
1.5 Operating temperature range:	-40℃ To +85℃			
1.6 Storage temperature range:	-55℃ To +125℃			
1.7 Temperature Coefficient	-0.04×10 ⁻⁶ / °C ² max			
1.8 Turn-over temperature::	+25℃±5℃			
1.9 Loading capacitance (CL) :	4.0pF			
1.10 Drive level:	0.5uW max			
1.11 Shunt Capacitance:	1.1pF Typical			
1.12 Motional Capacitance:	4.1fF Typical			
1.13 Insulation resistance :	More than 500M ohms			
1.14 Aging:	±3 ppm/Year Max			
	Ta=+25℃±3℃,first year			
1.15 Dimensions and marking	Refer to page.3			
1.16 Emboss carrier tape & reel	Refer to page.5 and page.6			
1.17 Note				
Standard atmospheric conditions Jnless otherwise specified, the standard range of atmospheric conditions for making measurement				

Unless otherwise specified, the standard range of atmospheric conditions for making measurement and tests are as follow: Ambient temperature : $25\pm3^\circ$ C

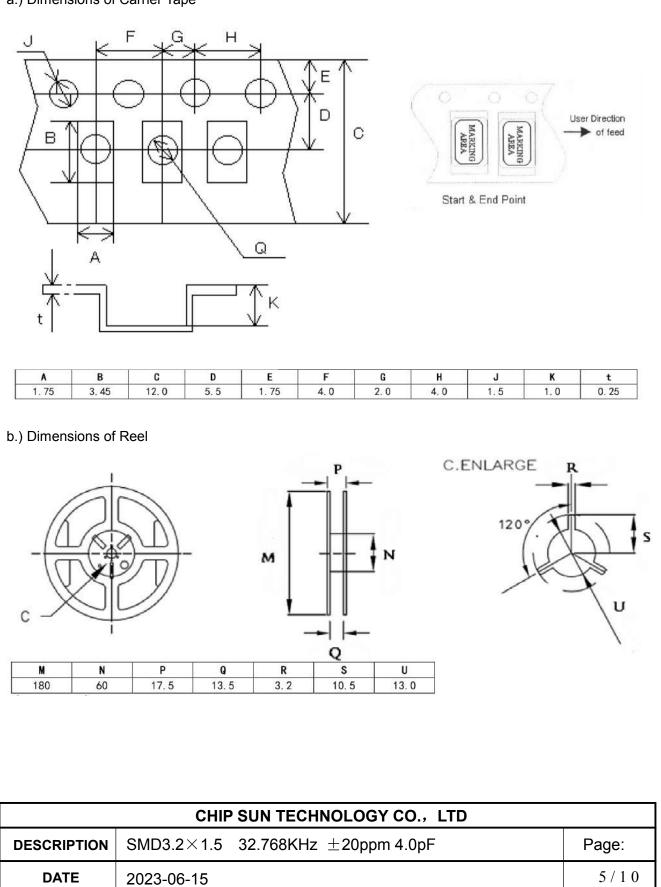
Relative humidity : 40%~70%

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3 CARRIER TAPE & REEL

a.) Dimensions of Carrier Tape



a.) Storage condition

Temperature: -55deg.C To +125deg.C Relative Humidity: 80% Max.

b.) Standard packing quantity

3,000PCS / REEL

c.) Material of the tape

Таре	Material
Carrier tape	A- PET
Top tape	Polyester

d.) Label contents

.The type of product .Our specification No. .Your Part No. .Lot No. .Nominal Frequency .Quantity .Our Company Name

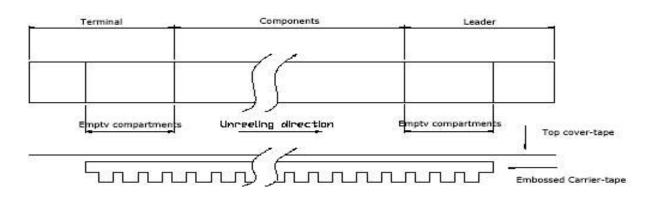
Sticks label for every reel.

PART NUMBER		
PO. NO.:		
PR. NO.:		
HOLDER TYPE		
FREQUENCY		
REMAKS		
QUANTITY		
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e.) Taping dimension

1 0	r0				
Leader	Cover-tape	The length of cover-tape in the leader is more than 400 mm including empty embossed area.			
Leader	Carrier-tape	After all products were packaged, must remain more than twenty pieces or 400 mm empty area, which should be sealed by cover-tape.			
Terminal	Cover-tape	The tip of cover-tape shall be fixed temporary by paper tape and roll around the core of reel one round.			
	Carrier-tape	The empty embossed area which are sealed by top cover-tape must remain more the 40 mm.			



f.) Joint of tape

The carrier-tape and top cover-tape should not be jointed.

g.) Release strength of cover tape

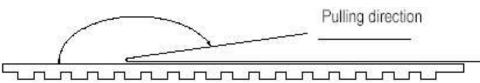
It has to between 0.1N to 0.7N under following condition.

Pulling direction 165° to 180°

Speed 300mm/min.

Otherwise unless specified.

165°∼ 180°



Other standards shall be based on JIS C 0806-1990.

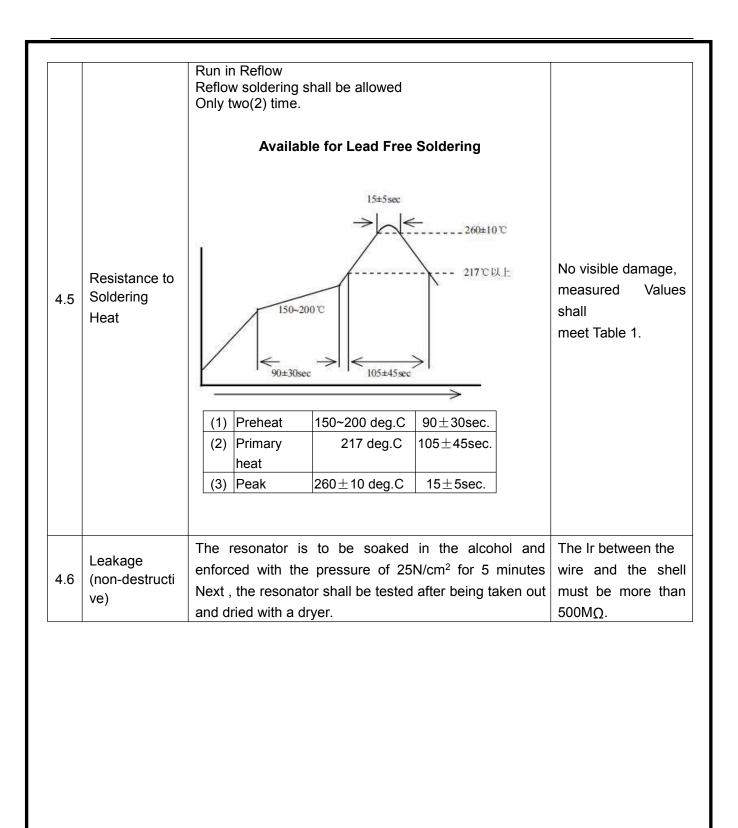
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4. Mechanical Endurance: Provided that measurement shall be carried out

			Performance
	Test Item	st Item Condition of Test	
4.1	Shock (Destructive)	Resonator shall be tested after 3 times random drops from the height of 75 cm onto hard wooden broad of thickness more than 30 mm.	Requirements No visible damage, Measured Values shall meet Table 1.
4.2	Vibration (Destructive)	Subject resonator to following vibration Frequency:10-55Hz Amplitude: 0.75mm Cycle time: 1~2min(10-55-10Hz) Duration: 3 mutually perpendicular Planes in each 2 hoursDirection: X, Y, Z	No visible damage, measured Values shall meet Table 1.
4.3	Terminal Strength (Destructive)	Pulling: body of resonator shall be fixed, and 0.5kg of tension weight shall be supplied gradually to axial direction of lead terminals for 30 seconds Bending: body of resonator shall be fixed, And 90 ℃ bending at a distance of 2.5±0.5 mm from crystal main body shall be given being supplied 250g tension weight. after that, lead terminals shall be straightened gradually. Then, the same bending and straightening shall be supplied to the opposite direction in the same axial.	The lead shall not be broken , measured Values shall meet Table 1.
4.4	Solder ability	Pre-heat temperature : $+150\pm10^{\circ}$ C Pre-heat time : $60\sim120$ s When the temperature of the specimen is reached at $+215\pm3^{\circ}$ C, it shall be left for 30 ± 1 sec. Peak temperature $240\pm5^{\circ}$ C Material: Pb-free (Sn-3.0Ag-0.5Cu) Flux : Rosin resin methyl alcohol solvent (1:4) The electrodes should be covered by a new solder at least 90% of immersed area.	No visible damage, measured Values shall meet Table 1.

afterletting it alone in the room temperature for 1 hour.

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5. Environmental Endurance: Provided that measurement shall be carried out afterletting it alone in the room temperature for 1 hour.

	ltem	Conditions	Specifications
5.1	Humidity	Should be satisfied after letting it alone at +60 $^\circ C\pm 2^\circ C$ in humidity of 85% \pm 5% for 240 hours.	No visible damage, measured Values shall meet Table1.
5.2	Storage in Low Temperature	Should be satisfied after letting it alone at $-30^{\circ}C \pm 2^{\circ}C$ for 240 hours.	No visible damage, measured Values shall meet Table1
5.3	Storage in High Temperature	Should be satisfied after letting it alone at $+85^{\circ}C \pm 2^{\circ}C$ for 240 hours.	No visible damage, measured Values shall meet Table1
5.4	Temperature Cycle	Should be satisfied after supplying the following temperature cycle (10 cycles). (Refer to Fig-4). Temperature shift from low to high, high to low shall be done in 1° /min.	No visible damage, measured Values shall meet Table1

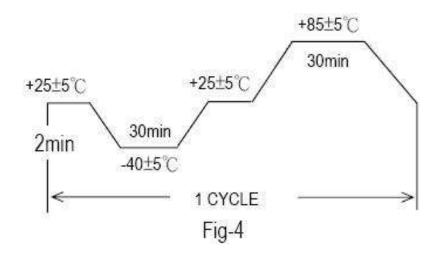


Table	1
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Test Item	Specification	Note
Frequency change (△f/fo)	\pm 5ppm	Reference to the initial value
C.I. (△R)	15%	Reference to the initial value

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